EDICON

Tuesday, March 20, 2018

08:30 - 05:00	Registration On Site						
ROOM	**402 A/B**	**403**	**405**	**406**	**407**	**401**	**EXPO Hall**
09:30 - 11:00	Plenary Session on 5G (Auditorium): Featuring Dr. Ying Peng, DaTang Telecommunication Technology & Industry Holding Co. Ltd.; Giampaolo Tardioli, Keysight; Christoph Pointner, Rohde & Schwarz; & Luke Schreier, National Instruments						
11:00 -12:00	Lunch Break: Exhibition Floor						
Technical Sessions							
	5G	**Test & Measurement**	**Signal Integrity**	**Simulation & Modeling**	**RF & MW Design/T&M**	**ACB Regulatory Training** *Additional Registration Required*	
12:05 - 12:25	5G Track Featured Keynote: Mobile Radio Transformation in the Age of 5G: A Perspective on Technologies and Solution (147) Peter Rabbeni, GLOBALFOUNDRIES	Measurement of Beamforming Antenna in Transmit Mode (45) Thilo Bednorz, Rohde & Schwarz	Using 3D EM Simulation Tool to Help Pre & Post-Layout Simulation for Improving the Signal Integrity in High Speed SERDES Lane (68) Kris Liu, Analog Devices	Simulation of BER, EVM and ACPR Performance Under Proposed 5G Modulation Waveforms (50) Milton Lien, National Instruments	RF-Connectivity Concepts Addressing the Requirements of Future RF-Energy Applications (36) Hannes Grubinger, HUBER+SUHNER AG	IoT (11:20 - 12:00)*	
12:30 - 12:50	Components for 5G – What's New? (62) Markus Loerner, Rohde & Schwarz	Tricks for Antenna Gain Measurements (28) Andrew Yuk Choi Ko, Keysight	Master Your 400G, Characterization and Simplifies PAM4 Testing (150) Steve Sekel, Keysight	Status of Current Reliability Modeling Solutions (22) Long Ma, Keysight	Symmetric and Reciprocal Two-Port 3x Through: Theory and Application (11) Joshua Wan, Xpeedic Technology Inc.	Break	
12:55 - 13:15	Wideband mm-Wave 5G Antenna Solution for Mobile Device (21) Bin Yu, Speed Wireless Technology Co. Ltd.	Precise and Fast Noise Figure Measurement of Multiport Devices (100) Volker Herrmann, Rohde & Schwarz	Via Simulation and Research in High Speed (23) Xiuguo Jiang, Keysight	Accurate GaN Modeling for RF Power Amplifier Design Enablement (77) Amit Dikshit, Ampleon Netherlands BV	The Future of IoT Wireless Technology: Smarter Testing from Characterization to Production (60) Fangze Tu, National Instruments	Fast SAR Measurement -- IEC PAS 63151 (13:00 - 13:45)*	
13:20 - 13:40	5G 3GPP NR Signal Generation and Analysis (95) Martin Schmähling, Rohde & Schwarz	Development and Testing of High Accuracy Reference Antennas for Millimeter Wave On-Chip Antenna Measurements (98) Lars Jacob Foged, Microwave Vision Group, MVG	PCIe Gen4 / Gen5: How to Measure the Real Jitter Performance of an SSC Clock (113) Martin Stumpf, Rohde & Schwarz	Using Automatic De-Embedding Technology to Complete the Accurate Extraction of Simulation Model (138) Xu Yue, Keysight	Millimeter Wave Challenges and Calibration (43) Stewart Forsyth, Keysight		
13:45 - 14:15	Tea Break: Exhibition Floor						
Workshops						**ACB EMC Training**	
14:15 - 14:55	Panel: 5G MIMO	Rapid Design Method for GaN HEMT Asymmetric Doherty PA (174) NI/AWR	Channel Emulation and Testing Base on SDR Platform (123) Sample Technology (Shanghai) Co. Ltd.	Mastering IoT Testing Challenges (140) MVG/Microwave Vision	DYNAX GaN Technical Advantage and Recommended Applications (109) DYNAX	FCC/ISED (14:15 - 15:15)*	
15:00 - 15:40	All-Silicon Active Antennas for High Performance 5G Terminals (136) Anokiwave	Smart Partitioning of Signal Chain for Massive MIMO Systems (163) Analog Devices	Using Vector Agile Frequency Technique to Improve the Fidelity of Radar Signal Simulation (26) Keysight	Mixed Signal Non-Linear Network System for Arbitrary Impedance Application (141) Maury Microwave	Vector Network Analysis Multiport Testing: Challenges and Solutions (89) Rohde & Schwarz		
15:45 - 16:25	An Overview of 5G New Radio - From Prototyping to Test (143) National Instruments	Evaluation of Key RF FEM Design Blocks with Cutting-Edge SOI Technology (142) GLOBALFOUNDRIES	Noise Parameter Characterization Techniques for mmWave Applications (129) Maury Microwave Corp.	Innovative LTCC Product Design & Development (158) Mini-Circuits	Direct Conversion with High-Speed Data Converters and K-Band Application (16) Marc Stackler, Teledyne e2v	RED (15:45 - 16:45)*	
16:30 - 17:10	Crucial Points of Device Models for 5G Semiconductor/MMIC Design Consideration (124) Win Semiconductors Corp.	5G PA and FEM Test (30) Keysight	On the AM/PM Distortion of GaN HEMT (14) MACOM	Low Cost Solutions for (5G) Wireless and Massive MIMO Testing (157) Mini-Circuits	Autonomous Vehicle Radar Simulation: From Antenna Design to Dynamic Road Scene Testing (161) ANSYS		
17:20	Drawing on Show Floor/Best Product Awards						
17:30	Welcome Reception for Conference Attendees (Badge Required)						

EXHIBIT HALL OPEN 11:00 - 17:30

EDICON

Wednesday, March 21, 2018

08:00 - 05:00	Registration On Site						
ROOM	**402 A/B**	**403**	**405**	**406**	**407**	**401**	**EXPO Hall**

Technical Sessions

	Radar & Defense	RF & MW Design	Test & Measurement	EMC/EMI	Signal Integrity	ACB EMC Training for Chinese iNARTE Members * Additional Registration Required	EXHIBIT HALL OPEN 10:00 - 17:00
09:00 - 09:20	Radar Technology for IoT Applications (41), Henry Lau, Lexiwave Technology Inc.	The Taiji Theory of Direct-Conversation and Super-Heterodyne Architectures in RF Design (51) Wei Lin, National Instruments	Phased Array Antenna Control Components (64) Markus Loerner, Rohde & Schwarz	Research of the EMC Test Method for the High-Power and Integral Antenna Equipment with Multi-Antenna and Multi-Channel (57) Li Ge, ZTE Corp.	New Test Vehicle Design for High-Performance Laminate Materials (118) Eric Bogatin, Teledyne LeCroy	EMC Basics (9:20 - 10:20)*	
09:30 - 10:30	Plenary Session Room 402A/B: Featuring Dr. Guochun (GC) Liang, Pivotone Communications; Dr. Klaus Werner, RF Energy Alliance; & Rainer Horn, SpaceTec Partners						
10:30 - 10:50	Tea Break: Exhibition Floor						

	Radar & Defense	RF & MW Design: Amplifiers	Test & Measurement	Simulation & Modeling	Signal Integrity/ Power Integrity		
10:55 - 11:15	Electronic System-Level (ESL) Automotive Radar Design and Optimization (67) Jin Zhang, Keysight	Harmonic Injection and Elimination (HIE) GaN HEMT Doherty Power Amplifiers Design for High Efficiency (17) Zhancang Wang, Ericsson	Overcome the Challenges of Low-IF Mixer/Converter Measurements (12) Ning Cheng, Keysight	MIMO Antenna Synthesis (47) Lars Van Der Klooster, National Instruments	Comprehensive Signal and Power Co-Investigation on DDR4 Simulation and Measurement (61) Nick Huang, ASUSTek COMPUTER INC.		
11:20 - 11:40	Automotive Radar: Signal Generation and Analysis (91) Hui Wu, Keysight	Measurement and Behavioral Modeling of Power Amplifiers under Mismatched Loads, (139) Li Tong, Keysight	Evaluating High-Performance Direct RF Sampling Data Converters (63) Markus Loerner, Rohde & Schwarz	Multiharmonic and Bilateral Transistor's Behavioral Models for RF & MW PA Design (53) Zacharia Ouardirhi, AMCAD Engineering	PDN Challenges in High Speed PCB Design (111) Lu Xian, ZTE Corp.	EMC Design and Antennas (10:50 - 11:50)*	
11:45 - 12:05	State-of-the-Art Automotive Radar Measurement Techniques (9) Hieng Ling Tie, Keysight	Testing Power Amplifiers for 802.11ax, Power Amplifiers EVM Testing Impairments and Digital Pre-Distortion (DPD) Technology (24) Middle Wen, LitePoint	Vehicle Networking Simulation Test Solution (Millimeter-Wave Automotive Radar Target Simulation Test Platform) (149) Yu Xian, Keysight	The Theory and Challenges for Robot Automatic Tuning (RAT) of Microwave Filtering Networks (37) KeLi Wu, The Chinese University of Hong Kong, Department of Electronic Engineering	Update on the IEEE P370 Standards Committee on a Draft Spec for Electrical Characterization of Interconnects to 50 GHz (117) Eric Bogatin, Teledyne LeCroy		
12:05 - 13:00	Lunch Break: Exhibition Floor						

Workshops & Panels / **ACB EMC Training**

13:05-13:45	Panel: GaN Goes Global	Advanced Modeling Tools for RF and Microwave System Simulation (52) AMCAD Engineering	How to Use Wideband High Resolution Phase & Amplitude Controlled Matrix to Help the R&D and Test Related to 5G (126) Mitron	New mm-Wave Test & Measurement Solution for More Accurate, Compact and Affordable Designs (56) Farran Technology	What to Consider When Selecting PCB Materials for Optimum Performance at 77 GHz (159) Rogers Corp.	Shielding/Grounding/ Grounding Technical (13:30 - 14:30)*	
13:50 - 14:30	The Use of GaN/Si Commercial Process to Achieve mmW LNA and PA at Low Cost (168) Sichuan YiFeng	RF Test of 5G mmWave and Ultra-Wideband PA and Digital Pre-Distortion (DPD) Verification (38) Keysight	Advanced Front End Module Test Including Wide Band Impedance Control (70) Focus Microwaves	Get the Most Out of Your Data Converter Design (66) Rohde & Schwarz	Designing and Optimizing a High-Efficiency RF Front End with Digital Pre-Distortion (DPD) (120) Richardson RFPD Electronics		Poster Session 14:00 - 15:00 (Exhibit Hall)
14:35 -15:15	Testing and Optimization to Enhance NB-IoT Product Life Time (131) Keysight	Effect of Balun Amplitude and Phase Imbalance on RF System Performance (114) Integrated Device Technology (IDT)	Application of Power Amplifier in Radar and Electronic Countermeasures (166) Beijing Xutec Technology	Applications for 110 GHz Load Pull and Noise Parameter Extraction (72) Focus Microwaves	SAIC Foundry Service for RF Application (164) Xiamen Sanan	Spectrum Analysis Measurement (15:00 - 16:00)*	
15:20 - 16:00	Design Considerations for 5G mm-wave Products (125) Win Semiconductors Corp.	Test Technology Development and Challenges in THz Engineering Applications (167) CETC 41	Material Selection for High Frequency PCB in the 5G Era (160) Shengyi Technology	GaN/SiC HEMT Process in the Mainland China (128) Chengdu Hiwafer Semiconductor	GaN RF Devices for Next-Generation Wireless Communication (165) Xiamen Sanan		
16:00 - 17:00	Happy Hour: Exhibition Floor						

EDICON

Thursday, March 22, 2018

08:00 - 14:00	Registration On Site					
ROOM	**402 A/B**	**403**	**405**	**406**	**407**	**EXPO Hall**
	Technical Sessions & Panels					
	5G	**Test & Measurement**	**RF & Microwave Design**	**Simulation & Modeling**	**Short Course**	
09:05 - 09:25	Developing Proof of Concept Systems for 5G (54) Fangze Tu, National Instruments	5G mmWave Massive MIMO Over-The-Air (OTA) Test: Technical Challenges and Prototype System (148) Wen Zhu, Keysight	Solid State RF Energy – Inroads to the Industrial Market, Panel Discussion, Klaus Werner kw tec b.v. & RF Energy Alliance	Automatic Design and Verification Flow of PA Modeling and Digital Pre-Distortion (156) Wu Jiarui, Keysight	Short Course: Essential Principles of Power Integrity Measurements Eric Bogatin, Teledyne LeCroy Runs from 9:05-11:50	EXHIBIT HALL OPEN 10:00 - 15:00
09:30 - 09:50	RF Technology for 5G mmwave Radio (79) Thomas Cameron, Analog Devices	Increasing Measurement Accuracy of VNAs in the THz Range (46) Thilo Bednorz, Rohde & Schwarz		Twisted Cable Fast Modeling and Simulation (44) Chenzing Zhao, Xpeedic Technology		
09:55 - 10:15	Overview of 5G UE OTA Test Challenges and Methods (151) Jing Ya, Keysight	Advanced Methods to Analyze Ultra Wide Automotive Radar Signals (94) Martin Schmähling, Rohde & Schwarz		Component - Level Via Modeling and Optimization Technology (34) Rui Wang, Xpeedic Technology		
10:20 - 10:40	Creating Far-Field Condition at a Tenth of Far-Field Distance: an Innovative Technique for 5G OTA Measurement (81) Benoît Derat, Rohde & Schwarz	5G Massive MIMO Measurement Challenges and Test Solutions (152) Kong Hongwei, Keysight		Entire Equivalent Model and Design Method for RF Testing System Signal Integration (65) Lung Shu Huang, Jthink Technology Ltd.		
10:40 - 11:00	Coffee Break: Exhibition Floor					
	5G	**RF & Microwave Design**	**Signal Integrity**	**Test & Measurement**		
11:05 - 11:25	5G mmWave OTA Testing (121) Aleksis Anterow, Microwave Vision Group	Medical Wireless Coexistence Between Medical and IoT Devices (153) Chris Kelly, Keysight	DDR4 Design and Simulation (19) Jun Lu, EDADOC	Trends in mmWave Devices, ICs and Packaging for Electronics Test and Measurement (82) Di Liu, Keysight	Short Course: Essential Principles of Power Integrity Measurements Eric Bogatin, Teledyne LeCroy Runs from 9:05-11:50	
11:30 - 11:50	Far-Field Distance and OTA Characterization of 5G Mobile Devices (122) Benoît Derat, Rohde & Schwarz	sub-6 GHz 5G Device Requirement in GTI (155) Yang Huaizhi, Keysight	Correlation Between Measurement and 3D EM Simulation for 25 Gbps and Beyond Backplane Passive Channel Characterization (74) Keysight	Techniques for Measuring 5G New Radio Components (154) Sheri DeTomasi, Keysight		
11:55 - 12:15	Panel: 5G mmwave OTA Testing	Performance Differentiated Transmit (Tx) Radio Frequency Frontends (RFFE) (85) Gareth Lloyd, Rohde & Schwarz	High-Speed Digital Bus Standard Test Technology Updates, from PCIE4.0 to Type-C Interface (162) Huang Teng, Keysight	Advanced III/V MMIC Process and Product Roadmaps for Terahertz Applications (169) Sichuan YiFeng		
12:20 - 12:40		Design and Optimization of Biasing Networks for Wideband High Power Amplifiers (76) Osman Ceylan, Ampleon	Using Eye Contours in Scopes to Analysis High-Speed Serial Digital Signals (75) Qiujie Lu, Keysight			